

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT She t 1 of 1**

Docket No. B0004/7110

Applicant: Jochen Franzen  
Serial No: 10/624,913  
Filed: July 22, 2003  
For: IONIZATION AT ATMOSPHERIC PRESSURE FOR MASS SPECTROMETRIC ANALYSES  
Examiner: Not Yet Assigned  
Art Unit: Not Yet Assigned

**U.S. PATENT DOCUMENTS**

Exam Inits	Cite No.	Patent Number	Kind Code	Patentee or Applicant Name	Issue Date
<i>JF</i>		5,750,988	B1	Apffel et al.	5/1998
<i>JF</i>		5,736,740	B1	Franzen	4/1998
<i>JF</i>		5,663,561	B1	Franzen et al.	9/1997
<i>JF</i>		5,818,041	B1	Mordehai et al.	10/1998
<i>JF</i>		5,877,495	B1	Takada et al.	3/1999
<i>JF</i>		6,121,608	B1	Takada et al.	9/2000
Exam Inits	Cite No.	Publication Number	Kind Code	Patentee or Applicant Name	Publication Date
		2002/0011560	A1	Sheehan et al.	1/2002

**FOREIGN PATENT DOCUMENTS**

Exam Inits	Cite No.	Cy	Number	Kind Code	Patentee or Applicant Name	Publication Date	T
<i>JF</i>		EP	0 762 473	A3	Hitachi, Ltd.	9/6/1996	<input type="checkbox"/>
<i>JF</i>		DE	196 08 963	A1	Bruker-Franzen Analytik GmbH	3/8/1996	<input type="checkbox"/>
<i>JF</i>		DE	100 44 655	A1	GSF - Forschungszentrum für Umwelt und Gesundheit GmbH	9/9/2000	<input type="checkbox"/>
<i>JF</i>		DE	100 42 394	A1	IUT Institut für Umwelttechnologien GmbH	8/29/2000	<input type="checkbox"/>
<i>JF</i>		DE	195 20 276	A1	Bruker - Franzen Analytik GmbH	6/2/1995	<input type="checkbox"/>
<i>JF</i>		WO	00/52735	A1	Bruker Daltronics, Inc.	9/8/2000	<input type="checkbox"/>
							<input type="checkbox"/>

Examiner  
SignatureDate  
Considered

8/19/04

